

SMD POWER INDUCTOR

- CS SERIES -

■ FEATURES

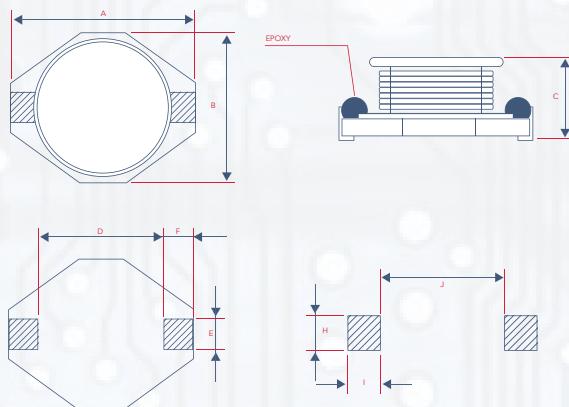
- With magnetically shielded against radiation
- CS1608 can help to achieve longer battery life significantly in handheld communication devices.
- CD3316/5022 designed for the higher current requirements of portable computers.
- CS1608 used ceramic base with gol=plating
- CS3316/5022 used LCP plastic base



■ APPLICATIONS

- Portable Telephones
- Personal Computers
- DC/DC Converters, etc.
- Other Various Electronic Appliances

■ MECHANICAL DIMENSION



■ CHARACTERISTICS

- Saturation Rated Current (IDC): The DC current when the inductance becomes 10% lower than its initial value. ($T_a=25^\circ\text{C}$)
- Temperature Rise Current (I_{rms}): The actual current when temperature of coil becomes $\Delta 40^\circ\text{C}$. ($T_a=25^\circ\text{C}$)
- Operating temperature range: $-40\sim 85^\circ\text{C}$

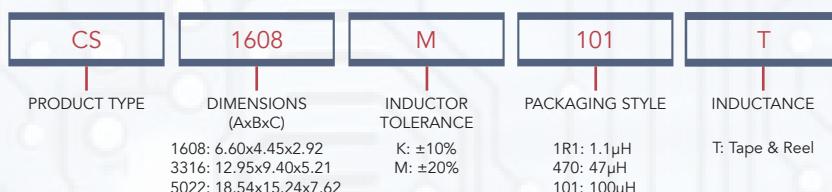
TYPE	A (MAX)	B (MAX)	C (MAX)	D	E	F	H	I	J
CS1608	6.60	4.45	2.92	4.32	1.27	1.02	3.56	1.40	4.06
CS3316	12.95	9.40	5.21	7.62	2.54	2.54	2.79	2.92	7.37
CS5022	18.54	15.24	7.62	12.70	2.54	2.54	2.79	2.92	12.45

■ INDUCTANCE AND RATED CURRENT RANGES

- Electrical specifications at 25°C

CS1608	1.0 μH ~ 10000 μH	1.4 ~ 0.02A
CS3316	1.0 μH ~ 10000 μH	5.6 ~ 0.32A
CS5022	1.0 μH ~ 10000 μH	20.0 ~ 0.80A

■ PART NUMBERING





ELECTRICAL CHARACTERISTICS

- CS1608 TYPE

CODES	L (μ H)	TOLERANCE	TEST CONDITION		DCR (Ω) MAX	SRF REF (MHz)	Q MIN.	IDC (A) MAX.	
			L	Q				I SAT	I RMS
1R0	1.0	M	100KHz, 0.1V	200KHz, 0.1V	0.040	250	30	1.40	3.00
1R5	1.5	M	100KHz, 0.1V	200KHz, 0.1V	0.045	125	30	0.93	2.30
2R2	2.2	M	100KHz, 0.1V	200KHz, 0.1V	0.050	120	40	0.92	1.80
3R3	3.3	M	100KHz, 0.1V	200KHz, 0.1V	0.055	120	40	0.75	1.60
4R7	4.7	M	100KHz, 0.1V	200KHz, 0.1V	0.060	105	40	0.58	1.40
6R8	6.8	M	100KHz, 0.1V	200KHz, 0.1V	0.065	50	40	0.58	1.20
100	10	M	100KHz, 0.1V	200KHz, 0.1V	0.075	38	40	0.37	1.00
150	15	M	100KHz, 0.1V	100KHz, 0.1V	0.090	33	40	0.31	0.80
220	22	M	100KHz, 0.1V	100KHz, 0.1V	0.11	25	40	0.30	0.70
330	33	M	100KHz, 0.1V	100KHz, 0.1V	0.19	20	40	0.24	0.60
470	47	M	100KHz, 0.1V	100KHz, 0.1V	0.23	20	40	0.24	0.50
680	68	M	100KHz, 0.1V	100KHz, 0.1V	0.29	15	40	0.17	0.40
101	100	M	100KHz, 0.1V	100KHz, 0.1V	0.48	10	40	0.13	0.30
151	150	M	100KHz, 0.1V	100KHz, 0.1V	0.59	9	40	0.10	0.26
221	220	M	100KHz, 0.1V	100KHz, 0.1V	0.90	6	40	0.10	0.22
331	330	M	100KHz, 0.1V	100vKHz, 0.1V	1.40	5	40	0.07	0.20
471	470	M	100KHz, 0.1V	100KHz, 0.1V	1.80	4	40	0.06	0.19
681	680	M	100KHz, 0.1V	100KHz, 0.1V	2.20	3	40	0.06	0.18
102	1000	M	100KHz, 0.1V	100KHz, 0.1V	3.40	2	40	0.05	0.15
152	1500	M	100KHz, 0.1V	100KHz, 0.1V	4.20	2	50	0.04	0.12
222	2200	M	100KHz, 0.1V	100KHz, 0.1V	8.50	2	50	0.03	0.10
332	3300	M	100KHz, 0.1V	100KHz, 0.1V	11.0	1	50	0.02	0.06
472	4700	M	100KHz, 0.1V	100KHz, 0.1V	13.9	1	50	0.02	0.04
682	6800	M	100KHz, 0.1V	100KHz, 0.1V	25.0	1	50	0.02	0.02
103	10000	M	100KHz, 0.1V	100KHz, 0.1V	32.8	0.8	50	0.02	0.08

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ELECTRICAL CHARACTERISTICS

- CS5022 TYPE

CODES	L (μ H)	TOLERANCE	TEST CONDITION	DCR (Ω) MAX	IDC (A) MAX.
1R0	1.0	M	100KHz, 0.1V	0.021	5.6
1R5	1.5	M	100KHz, 0.1V	0.022	5.2
2R2	2.2	M	100KHz, 0.1V	0.032	5.0
3R3	3.3	M	100KHz, 0.1V	0.039	3.9
4R7	4.7	M	100KHz, 0.1V	0.054	3.2
6R8	6.8	M	100KHz, 0.1V	0.075	2.8
100	10	M	100KHz, 0.1V	0.101	2.4
150	15	M	100KHz, 0.1V	0.150	2.0
220	22	M	100KHz, 0.1V	0.207	1.6
330	33	M	100KHz, 0.1V	0.334	1.4
470	47	M	100KHz, 0.1V	0.472	1.0
680	68	M	100KHz, 0.1V	0.660	0.9
101	100	M	100KHz, 0.1V	1.110	0.8
151	150	M	100KHz, 0.1V	1.550	0.6
221	220	M	100KHz, 0.1V	2.000	0.5
271	270	M	100KHz, 0.1V	4.600	0.42
331	330	M	100KHz, 0.1V	5.600	0.35
391	390	M	100KHz, 0.1V	6.600	0.34
471	470	M	100KHz, 0.1V	7.600	0.33
681	680	M, K	100KHz, 0.1V	9.000	0.31
102	1000	M	100KHz, 0.1V	8.300	0.32



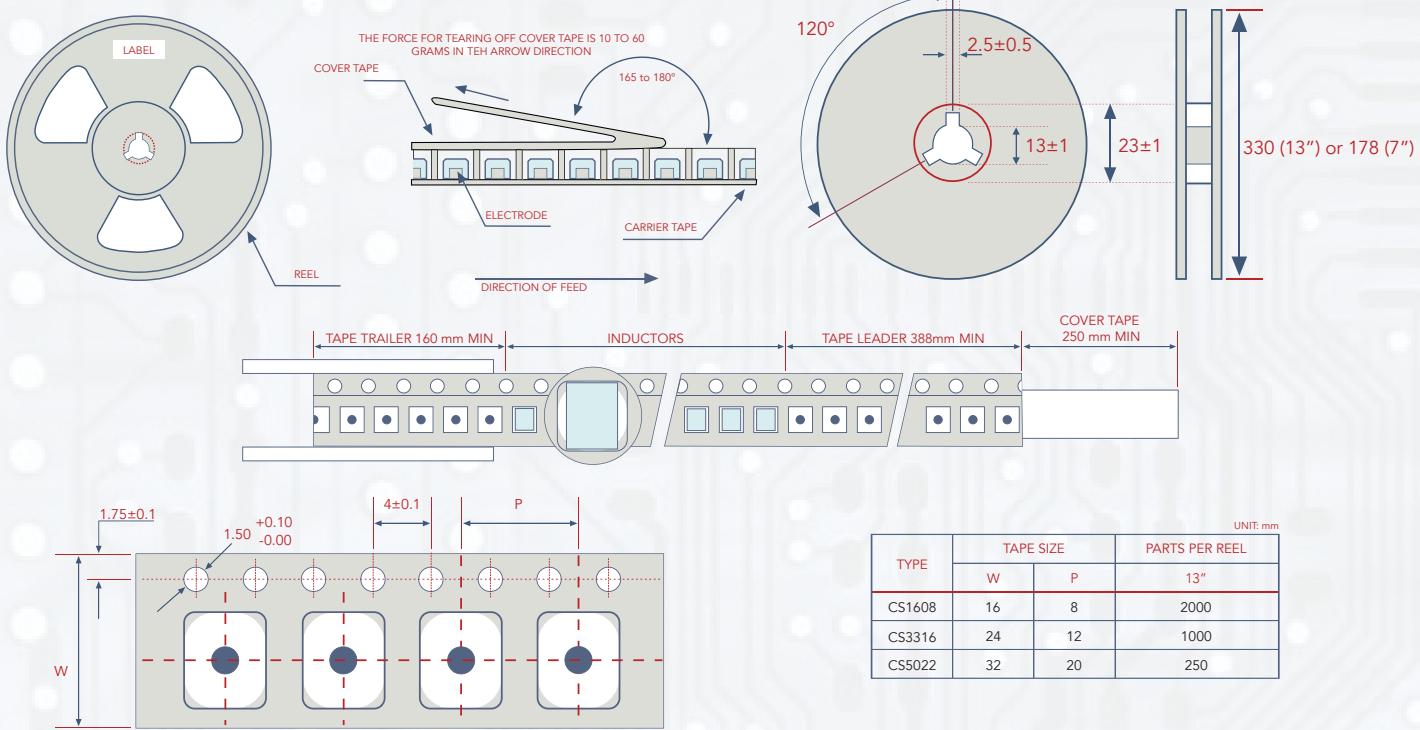
ELECTRICAL CHARACTERISTICS

- CS3316 TYPE

CODES	L (μ H)	TOLERANCE	TEST CONDITION	DCR (Ω) MAX	IDC (A) MAX.
1R0	1.0	M	100KHz, 0.1V	20.00	0.024
2R2	2.2	M	100KHz, 0.1V	11.00	0.026
3R3	3.3	M	100KHz, 0.1V	10.00	0.029
3R9	3.9	M	100KHz, 0.1V	8.50	0.030
4R7	4.7	M	100KHz, 0.1V	8.40	0.032
5R6	5.6	M	100KHz, 0.1V	8.30	0.034
6R8	6.8	M	100KHz, 0.1V	8.20	0.036
8R2	8.2	M	100KHz, 0.1V	8.10	0.038
100	10	M	100KHz, 0.1V	8.00	0.040
120	12	M	100KHz, 0.1V	7.10	0.046
150	15	M	100KHz, 0.1V	7.00	0.048
180	18	M	100KHz, 0.1V	6.10	0.056
220	22	M	100KHz, 0.1V	6.00	0.059
330	33	M	100KHz, 0.1V	5.00	0.075
390	39	M	100KHz, 0.1V	4.10	0.092
470	47	M	100KHz, 0.1V	4.00	0.097
560	56	M	100KHz, 0.1V	3.10	0.132
680	68	M	100KHz, 0.1V	3.00	0.138
820	82	M	100KHz, 0.1V	2.50	0.202
101	100	M	100KHz, 0.1V	2.40	0.207
121	120	M	100KHz, 0.1V	2.20	0.286
151	150	M	100KHz, 0.1V	2.10	0.293
180	181	M	100KHz, 0.1V	1.91	0.420
221	220	M	100KHz, 0.1V	1.90	0.470
271	270	M	100KHz, 0.1V	1.12	0.720
331	330	M	100KHz, 0.1V	1.10	0.780
391	390	M	100KHz, 0.1V	1.10	1.020
471	470	M	100KHz, 0.1V	1.10	1.080
561	560	M	100KHz, 0.1V	0.97	1.320
681	680	M	100KHz, 0.1V	0.96	1.400
821	820	M	100KHz, 0.1V	0.81	1.960
102	1000	M	100KHz, 0.1V	0.80	2.010

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■ TAPE AND REEL SPECIFICATIONS



■ SMT POWER INDUCTOR ENVIRONMENTAL SPECIFICATIONS

- General

ITEMS	SPECIFICATIONS
Shelf Storage Conditions	Temperature range: 15 ~28°C; Humidity: <80% relative Recommended product should be used within one year from the time of delivery.

- Environmental Test

TEST ITEMS	SPECIFICATIONS	TEST CONDITIONS / TEST METHODS
High Temperature Storage Test		Temperature 85±2°C Time: 48±2 hours, Tested after 1 hour at room temperature.
Low Temperature Storage Test	No case deformation or change in appearance. $\Delta L/L \leq 10\%$	Temperature -25±2°C Time: 48±2 hours, Tested after 1 hour at room temperature.
Humidity Test		Temperature 40±2°C, 90~95% relative humidity Time: 96±2 hours Tested after 1 hour at room temperature.
Thermal Shock Test		First -25°C 30 minutes then 25°C 10 minutes last 85°C 30 minutes, as 1 cycle. Go through 5 cycles. Tested after 1 hour at room temperature.

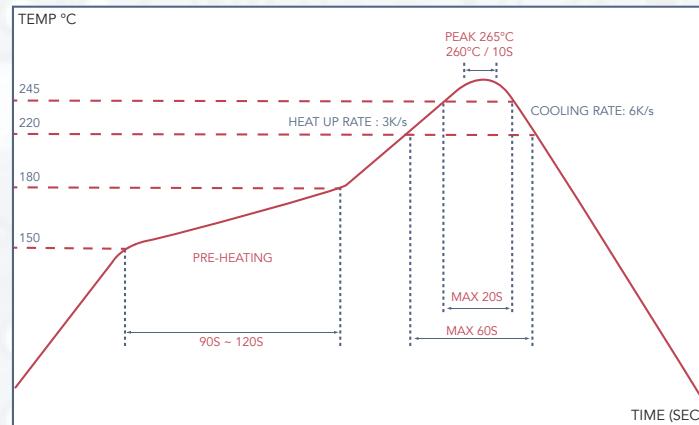


SMT POWER INDUCTOR ENVIRONMENTAL SPECIFICATIONS

- Mechanical Test

TEST ITEMS	SPECIFICATIONS	TEST CONDITIONS / TEST METHODS
Solderability Test	Terminal area must have 90% minimum solder coverage.	Product with Lead free terminal: Dip pads in flux then dip in solder pot at $245 \pm 5^\circ\text{C}$ for 3 seconds.
Resistance to Soldering Heat	No case deformation or change in appearance	Flux should cover the whole of the sample before heating, then be preheated for about 2 minutes over temperature of $130 \sim 150^\circ\text{C}$. Immersing to $260 \pm 5^\circ\text{C}$ for 10 seconds.
Vibration Test	No case deformation or change in appearance.	Apply frequency $10 \sim 55\text{Hz}$. 1.5mm amplitude in each of perpendicular direction for 2 hours.
Shock Resistance	$\Delta L/L \leq 10\%$	Drop down with 981m/s^2 (100G) shock attitude upon a rubber block method shock testing machine, for 1 time. In each of three orientations.

- The Condition of Reflow (recommendation):



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